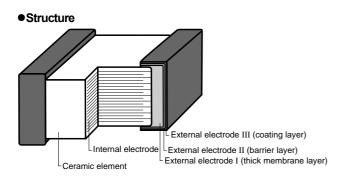
Multi-layer ceramic chip capacitors

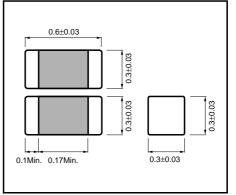
MCH03 (0603 size, chip capacitor)

Features

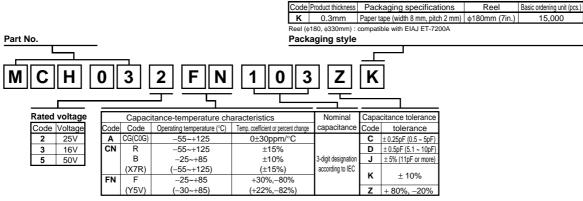
- 1) Small size (0.6 x 0.3 x 0.3 mm) makes it perfect for lightweight portable devices.
- Comes packed either in tape to enable automatic mounting.
- 3) Precise uniformity of shape and dimensions facilitates highly efficient automatic mounting.
- 4) Barrier layer and end terminations to improve solderability.



• External dimensions (Units : mm)



Product designation





MCH03

Ceramic capacitors

Capacitance range

For thermal compensation

Part number		MCH03
Conceitones (nE)	Temperature characteristics	(CG) (C0G)
Capacitance (pF)	Rated voltage (V) Tolerance	25V
0.5 0.75 1		
1.1 1.2 1.3		
1.5 1.6 1.8	C (± 0.25pF)	
2 2.2 2.4		
2.7 3 3.3		
3.6 3.9 4		
4.3 4.7 5		
5.1 5.6 6		
6.2 6.8 7	D (± 0.5pF)	
7.5 8 8.2		
9 9.1 10		

Part number		MCH03
Capacitance (pF)	Temperature characteristics	A (CG) (C0G
Capacitance (pr)	Rated voltage (V) Tolerance	25V
11		
12		
13		
15		
16		
18		
20		
22	J (±5%)	
24		
27		
30		
33		
36		
39		
43		
47		

Product thickness (mm) 0.3±0.03

High dielectric constant

Part number		MCH03	
Capacitance (pF)	Temperature characteristics	CN (R) (B) (X7R)	FN (F) (Y5V)
	Rated voltage (V)	25V	25V
	Tolerance	K (±10%)	Z (+80, -20%)
100 150 200			
330 470 680			
1,000 1,500 2,200			
4,700 10,000			

Product thickness (mm) 0.3±0.03



Ceramic capacitors

Characteristics

Class 1 (For thermal compensation)

	Temperature characteristics	4 (00) (000)	Test methods/conditions	
Item		A (CG) (C0G)	(based on JIS C 5102)	
Operating temp	perature	–55°C ~ 125°C		
Nominal capacitance (C)		Must be within the specified tolerance range.	Based on paragraph 7.8 and paragraph 9 Measured at room temperature and standard humidity,	
Dissipation factor (tanő)		100/(400+20C)% or less: Less than 30 pF 0.1% or less : 30 pF or larger	1000pF or less Measurement frequency : 1 ± 0.1MHz Measurement voltage :1 ± 0.1Vrms. Over 1000pF Measurement frequency : 1 ± 0.1KHz Measurement voltage :1 ± 0.1Vrms.	
Insulation resis	stance (IR)	10,000 M\Omega or 500 M\Omega $\cdot\mu\text{F},$ whichever is smaller	Based on paragraph 7.6 Measurement is made after rated voltage is applied for $60\pm5s$	
Withstanding voltage		The insulation must not be damaged.	Based on paragraph 7.1 Apply 300% of the rated voltage for 1 to 5s then measure.	
Temperature c	haracteristics	Within 0 \pm 30ppm/°C	The temperature coefficients in table 12, paragraph 7.12 are calculated at 20°C and high temperature.	
Terminal adher	rence	No detachment or signs of detachment.	Based on paragraph 8.11. 2. Apply 2N for 10 ± 1s in the direction indicated by the arrow.	
	Appearance	There must be no mechanical damage.	Chip is mounted to a board in the manner	
Resistance to vibration	Rate of capacitance change	Must be within initial tolerance.	shown on the right, subjected to vibration (type A in paragraph 8.2) and measured	
	Dissipation factor (tan)	Must satisfy initial specified value.	24 ± 2 hrs. later. Board	
Solderability		At least 3/4 of the surface of the two terminals must be covered with new solder.	Based on paragraph 8.13 Soldering temperature : 235 ± 5°C Soldering time : 2 ± 0.5s	
	Appearance	There must be no mechanical damage.		
	Rate of capacitance change	\pm 2.5% or \pm 0.25 pF, whichever is larger.	Based on paragraph 8.14. Soldering temperature: 260 ± 5°C Soldering time : 5 ± 0.5s Preheating : 150 ± 10°C for 1 to 2 min.	
Resistance to soldering	Dissipation factor (tan)	Must satisfy initial specified value.		
heat	Insulation resistance	10,000 M\Omega or 500 M\Omega $\cdot\mu\text{F},$ whichever is smaller		
	Withstanding voltage	The insulation must not be damaged.		
	Appearance	There must be no mechanical damage.		
-	Rate of capacitance change	\pm 2.5% or \pm 0.25 pF, whichever is larger.	Based on paragraph 9.3	
Temperature cycling	Dissipation factor $(tan \delta)$	Must satisfy initial specified value.	Number of cycles : 5	
	Insulation resistance	10,000 M\Omega or 500 M\Omega $\cdot\mu\text{F},$ whichever is smaller	– Capacitance measured after 24 \pm 2 hrs.	
Humidity load ⁻ test	Appearance	There must be no mechanical damage.	Based on paragraph 9.9	
	Rate of capacitance change	\pm 7.5% or \pm 0.75 pF, whichever is larger.	Test temperature: $40 \pm 2^{\circ}$ C Relative humidity: 90% to 95% Applied voltage : rated voltage Test time : 500 to 524 hrs. Capacitance measured after 24 \pm 2 hrs.	
	Dissipation factor (tan \delta)	0.5% or less		
	Insulation resistance	500M or 25M $\Omega \cdot \mu F,$ whichever is smaller		
High- temperature load test	Appearance	There must be no mechanical damage.	Based on paragraph 9.10 Test temperature : Max. operating temp. Applied voltage : rated voltage × 200% Test time : 1,000 to 1,048 hrs.	
	Rate of capacitance change	\pm 3.0% or \pm 0.3 pF, whichever is larger.		
	Dissipation factor (tan \delta)	0.3% or less		
	Insulation resistance	1,000M Ω or 50M $\Omega \cdot \mu F,$ whichever is smaller	Capacitance measured after 24 ± 2 hrs.	



Ceramic capacitors

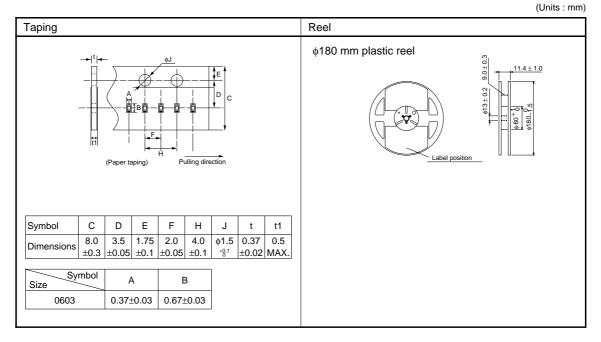
Class 2 (High dielectric constant)

_	lectric constant)				
Item	Temperature characteristics	CN (R) (B) (X7R)	FN (F) (Y5V)	Test methods/conditions (based on JIS C 5102)	
Operating temp	perature	−55°C ~ +125°C	−30°C ~ +85°C		
Nominal capacitance (C)		I Must be within the specified tolerance range.		Based on paragraph 7.8 Measured at room temperature and standard humidity	
Dissipation factor (tanδ)		2.5% or less (when rated voltage is 16V: 3.5% or less)	5.0% or less (when rated voltage is 16V: 7.5% or less)	Measurement frequency: 1 ± 0.1 kHz Measurement voltage : 1.0 ± 0.2 Vrms.	
Insulation resistance (IR)		10,000M Ω or 500M Ω · $\mu F,$ whichever is smaller		Based on paragraph 7.6 Measurement is made after rated voltage is applied for $60 \pm 5s$.	
Withstanding v	oltage	The insulation must not be damaged.		Based on paragraph 7.1 Apply 250% of the rated voltage for 1 to 5s then measure	
Temperature cl	haracteristics	Within ± 15%	+ 22, + 82%	The temperature coefficients in paragraph 7.12, table 8, condition B, are based on measurements carried out at 20° C, with no voltage applied.	
Terminal adher	Terminal adherence No detachment or signs of detachment		Based on paragraph 8. 11. 2. Apply 2N for 10 ± 1s in the direction indicated by the arrow.		
	Appearance	There must be no m	nechanical damage.	Chip is mounted to a board in the	
Resistance to vibration	Rate of capacitance change	Must be within initial tolerance.		manner shown on the right, subjected to vibration (type A in paragraph 8.2),	
	Dissipation factor $(tan \delta)$	Must satisfy initial specified value.		and measured 48 ± 4 hrs. later. Board	
Solderability		At least 3/4 of the surface of the two terminals must be covered with new solder.		Based on paragraph 8. 13 Soldering temperature : 235 ±5°C Soldering time : 2±0.5s	
	Appearance	There must be no m	nechanical damage.		
	Rate of capacitance change	Within ± 5.0%	Within ± 20.0%	Based on paragraph 8. 14. Soldering temperature : $260 \pm 5^{\circ}$ C	
Resistance to soldering	Dissipation factor (tanb)	Must satisfy initia	l specified value.		
heat	Insulation resistance	10,000M\Omega or 500M\Omega $\cdot\mu F,$ whichever is smaller		Soldering time: $5 \pm 0.5s$ Preheating: $150 \pm 10^{\circ}C$ for1 to 2 min.	
	Withstanding voltage	The insulation must not be damaged.			
Appearance		There must be no m	nechanical damage.		
Temperature	Rate of capacitance change	Within ± 7.5%	Within ± 20.0%	Based on paragraph 9.3 Number of cycles : 5	
cycling	Dissipation factor (tan δ)	Must satisfy initia	Must satisfy initial specified value. Capacitance measured a		
	Insulation resistance	10,000M\Omega or 500M\Omega $\cdot\mu\text{F},$ whichever is smaller			
Humidity load D	Appearance	There must be no m	nechanical damage.	Based on paragraph 9.9	
	Rate of capacitance change	± 12.5% or less	Within ± 30.0%	Test temperature : 40 ± 2°C Relative humidity : 90% to 95% Applied voltage : rated voltage Test time : 500 to 524 hrs.	
	Dissipation factor $(tan \delta)$	5.0% or less	7.5% or less (when rated voltage is 16V: 10.0%)		
	Insulation resistance	500M\Omega or 25M $\Omega\cdot\mu F,$ whichever is smaller		Capacitance measured after 48 ± 4 hrs	
High- temperature load test	Appearance	There must be no mechanical damage.			
	Rate of capacitance change	Within ± 10.0%	Within ± 30.0%	Based on paragraph 9.10 Test temperature: Max. operating tem Applied voltage : rated voltage × 200 Test time : 1,000 to 1,048 hrs.	
	Dissipation factor $(tan \delta)$	5.0% or less	7.5% or less (when rated voltage is 16V: 10.0%)		
	Insulation resistance	1,000MΩ or 50MΩ · μl	F, whichever is smaller	Capacitance measured after 48 ± 4 hrs.	



Ceramic capacitors

• Packaging specifications

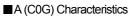


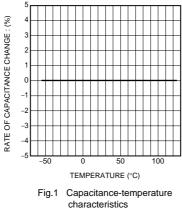


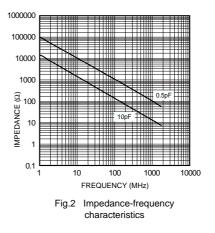
MCH03

Ceramic capacitors

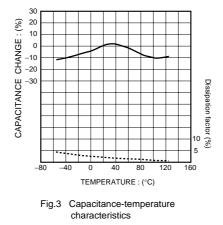
Electrical characteristics

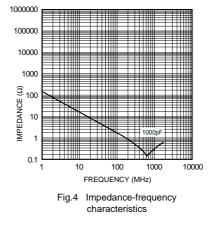






CN (X7R) Characteristics





FN (Y5V) Characteristics

